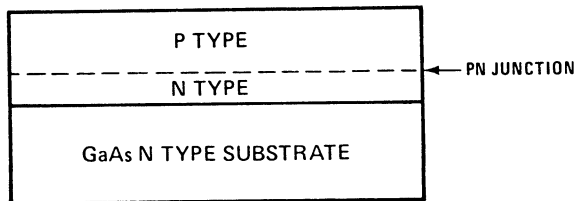


FIGURE 3
Typical Epitaxial Layer Growth

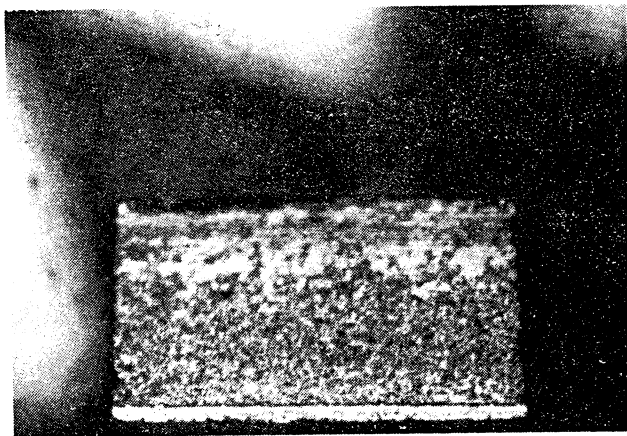


The nature of the Al in the melt is such that it is depleted or used up rapidly in the early stages of the epi growth. Concentration is virtually zero at the top of the P layer.

The substrate is then etched away with an etchant that readily dissolves GaAs. As the etchant contacts the N layer, the aluminum causes the etch rate to be slowed to 1/100th of the initial rate. This is convenient because it helps to ensure that the N layer is not materially etched.

After etching, appropriate ohmic contacts are added by evaporation techniques. A gold contact completely covers the P layer or backside, and a dot matrix contact is put on the N layer or topside. The chips are then sawed into their final size. A final etching is done to remove saw damage and to roughen the surface of the N layer which enhances light output. (See Figure 4.)

FIGURE 4
Typical Chip Cross Section



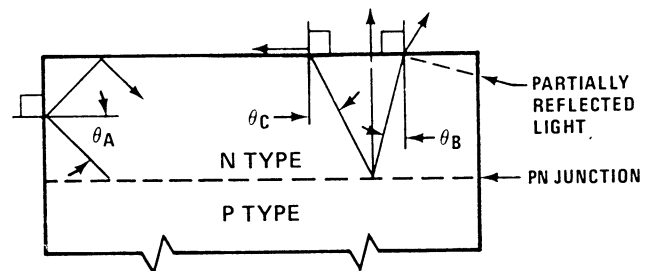
WHAT MAKES GaAlAs SUPERIOR?

The wavelength of the emitted light of an LED is related to the energy in the photons of light it emits. Also the higher the band gap energy of the semiconductor material, the higher the photon energy. Al atoms increase the band gap energy in proportion to the concentration which allows adjustment of the photon wavelength. By controlling this concentration, the wavelength can be varied to approximate the peak spectral response of a silicon phototransistor or 890 nanometers.

GaAlAs also has an improved radiation window. In order for an LED to emit more light, absorption of photons traveling through the material must be as low as possible. In other words, there must be a high probability that the photons generated at the junction will reach a surface and escape. For this to happen effectively, the photon energy must be less than the band gap energy of the material. In previous discussions, it was mentioned that Al atoms increase the band gap energy. The heaviest concentration of Al atoms is at the N layer surface with rapidly decreasing concentration toward the PN junction. Photons generated at the junction then travel a path through steadily increasing band gap energy levels until they reach the surface. This property ensures a much reduced chance of re-absorption of photons than does a material in which the band gap energy is constant from junction to surface such as GaAs.

One final plus, GaAlAs has an index of refraction which is slightly lower than GaAs. This affects the critical angle which defines the angle at which there is total internal reflection. (See Figure 5.)

FIGURE 5
Definition of Critical Angle



The critical angle is determined by the formula:

$$\text{SIN } \theta_C = \frac{n_1}{n_2} \quad \text{Where } n_1 \text{ is the index of refraction of air, or 1, and } n_2 \text{ is the index of refraction of the chip material.}$$

$$\begin{aligned} \text{With GaAs, } n_2 &= 3.6 \\ \text{SIN } \theta_C &= \frac{1}{3.6} \\ \theta_C &= 16^\circ \end{aligned}$$

$$\begin{aligned} \text{With GaAlAs, } n_2 &= 3.4 \\ \text{SIN } \theta_C &= \frac{1}{3.4} \\ \theta_C &= 17^\circ \end{aligned}$$

At angles less than the critical angle, there is partial reflection. (See angle θ_B in Figure 5.) At angles greater than the critical angle, there is total internal reflection. (See angle θ_A in Figure 5.)

There are ways of improving surface emission. One, mentioned earlier, is the post-dicing etch cleanup which roughens the chip surface. This increases the likelihood of photons striking the surface at less than the critical angle. Another improvement is the addition of a clear epoxy, anti-reflective, domed lens placed over the chip which actually enlarges the critical angle to approximately 24° .

RELIABILITY

Since GaAlAs and GaAs junctions are formed in the same manner, the chips should have the same reliability. Life tests to date indicate that this is true. Data shows that both GaAlAs and GaAs have from 5 to 8% degradation after 1,000 hours of maximum rated operation.

DRAWBACKS

GaAlAs has inherently high V_F . The higher the band gap energy, the higher the V_F must be to impart adequate energy to the electrons. Typical V_F for Optek's GaAs LED's at 100 mA is 1.5V vs. 1.75V for GaAlAs. This difference increases slightly at higher current levels.

CONCLUSION

Many power-starved optical assembly packages will be helped immediately by using GaAlAs. Special optosensor assemblies such as card readers, paper tape readers, paper sensors and precision shaft encoders will become easier to design.

Electronic assemblies which operated with an LED/sensor pair will benefit immediately.

- With optocouplers, higher current transfer ratios will be available, and the LED and sensor will not need to be mounted as close to each other which will allow higher isolation voltages.
- With reflective assemblies, reflective objects will be able to be sensed at greater distances than before.

- With interrupter assemblies, precise alignment and gap width will not be as critical. Since there is more light available, aperturing can be reduced for higher resolution or photosensor gain can be reduced for better signal-to-noise ratio and improved gain-bandwidth product.
- In battery-operated applications, a GaAlAs LED can replace a GaAs LED and provide the same light output at $\frac{1}{2}$ the current drive.
- Since the same light output can be produced at $\frac{1}{2}$ the current drive, GaAlAs LED's will have much longer operating life.

GaAlAs, with its superior performance, will give the designer more options and design flexibilities than were previously available.

DEAN WOLFE